

**Department of Electrical and Computer Engineering  
University of Wisconsin–Madison**

**ECE 553: Testing and Testable Design of Digital Systems  
Fall 2009**

GENERAL REFERENCE LIST

**L:** Indicates on reserve in the K. F. Wendt Library

**I:** Indicates available in Instructor's library

The text book contains an excellent set of references and is fairly comprehensive in providing the list of references for this course. The following is only a partial list that I consult often in my research.

I have added a list of web resources that may be of interest to many of you.

**BOOKS**

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## **PERIODICALS**

- IEEE Design and Test of Computers **I**
- IEEE Computer **I**
- IEEE Transactions on Computers **I**
- IEEE Transactions on Computer-Aided Design **I**
- IEEE Transactions on VLSI Systems
- IEEE Journal of Solid State Circuits **I**
- Proceedings of the IEEE (Occasional Tutorials) **I**
- Journal of Electronic Testing: Theory and Applications (JETTA) **I**
- IBM Journal of Research and Development
- ACM Transactions on Design Automation of Electronic Systems **I**

## **CONFERENCE PROCEEDINGS**

- International Test Conference (ITC) **I**
- International Conference on Computer-Aided Design (ICCAD) **I**
- International Conference on Computer Design (ICCD) **I**
- Design Automation Conference (DAC) **I**
- IEEE VLSI Test Symposium (VTS) **I**
- VLSI Design Conference (VLD) **I**
- IEEE Asian Test Symposium (ATS) **I**
- Custom Integrated Circuits Conference (CICC)
- International Symposium on Circuits and Systems (ISCAS)
- European Design and Test Conference (EDTC: after merger of EDAC with ETC) **I**
- European Test Symposium (ETS)

- Design, Automation and Test in European (DATE)
- IEEE Workshop on RTL Level Testing (WRTLTL)

**WEB RESOURCES** The www can be a very rich source of information provided it is used with caution and one knows about the reliability of the source. Following are the but few useful links and you can discover many more on your own.

- An excellent source of information about technology trends in this area and also lists the challenges that must be addressed by the silicon industry in the next decade is:  
<http://public.itrs.net>  
 This location points to *ITRS - information technology roadmap for semiconductors*. This is a very large document and be careful if you wish to print it.
- IEEE maintains its web site that links to many technical society activities. The site that may interest you is:  
<http://tab.computer.org/ttcc/>  
 This web site provides links to many testing related activities and links to conferences such as ITC, VTS, ATS, WRTLTL. Most of these conferences also maintain their own websites.
- Following three conference web sites are active at present and contain a glimpse of the forthcoming programs:  
<http://itctestweek.org/index.htm>  
<http://www.vlsiconference.com/vlsi2010/>  
<http://ats09.nchu.edu.tw/index.html>
- Nearly all major semiconductor and CAD/EDA companies, such as Intel, IBM, HP, Sun, Compaq, Mentor, SGI, Synopsis, Cadence, and many publishers of electronic news have test related material on their sites. You could use their search mechanisms to find about their test problems and solutions. Some of these websites allow you to ask technical questions. These questions are then answered by engineer(s) working in the area. A number of previously asked questions, including questions about testing their own products, may also be accessible.